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APPLICATION NO. CONT/PRIOR CLASS SUBCLASS ART UNIT EXAMINER 09/764683 2135 202

APPLICANTS :Fabrice.Walter Hugues Blangy

Method for testing an integrated circuit including hardware and/or software parts having a confidential nature

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	DRAWINGS	CLAIMS ALLOWED		
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G
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Form PTO-436A (Rev. 6/99)

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